

Search Notes

Application/Control No.

10/662,560

Examiner

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Applicant(s)/Patent under
Reexamination

HATANO, NAOYUKI

Art Unit

2182

SEARCHED

Class	Subclass	Date	Examiner
710	53	1/26/2006	ASC
N	54		
	55		
	56		
	57		
	62		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT PLUS; Inventor Search	9/15/2003	ASC